

Notice of References Cited	Application/Control No. 10/621,462	Applicant(s)/Patent Under Reexamination TAKASE, HIROSHI	
	Examiner Tanh Q. Nguyen	Art Unit 2182	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,154,832 A	11-2000	Maupin, Patrick E.	712/228
	B	US-6,772,354 B2	08-2004	Takenaka et al.	713/310
	C	US-2001/0044861 A1	11-2001	Niwa et al.	710/22
	D	US-6,639,914 B1	10-2003	Choi et al.	370/389
	E	US-2001/0015983 A1	08-2001	LU, SIMON	370/463
	F	US-6,151,651 A	11-2000	Hewitt et al.	710/315
	G	US-6,611,891 B1	08-2003	Hewitt et al.	710/306
	H	US-2002/0016973 A1	02-2002	Matsushita et al.	725/153
	I	US-6,839,347 B1	01-2005	Ishida et al.	370/389
	J	US-6,356,968 B1	03-2002	Kishon, Jakob	710/306
	K	US-6,324,178 B1	11-2001	Lo et al.	370/392
	L	US-6,425,021 B1	07-2002	Ghodrat et al.	710/22
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.